

SEE Symposium, May 2014

Hardness assurance for proton direct ionization-induced SEEs using a high-energy proton beam

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Supported by

- Lab Directed Research and Development program at Sandia National Laboratories, a multi-program laboratory operated by Sandia Corporation, a Lockheed Martin Company, for the United States Department of Energy, under contract DE-AC04-94AL85000. (SAND2014-3970 C)
- DTRA, under contract DTRA100277008.
- TRIUMF, which receives funding via a contribution agreement through the National Research Council of Canada.

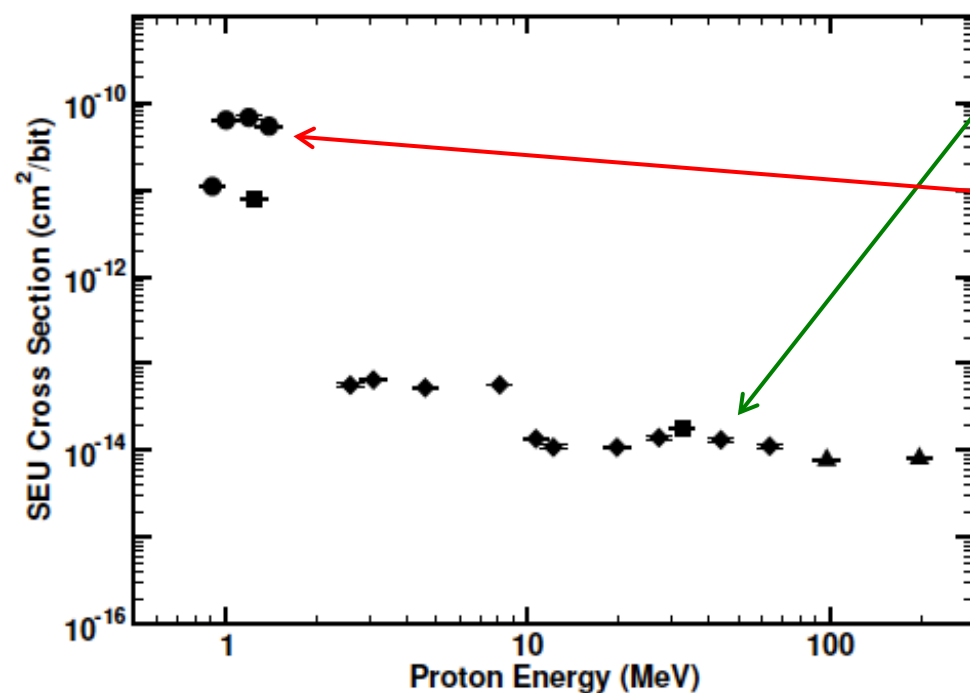


Outline

- **Background on proton direct ionization (PDI)**
- **Use of a high-energy proton beam to**
 - identify PDI susceptibility
 - predict PDI error rate
- **PDI angular effects**
- **Summary**

Background

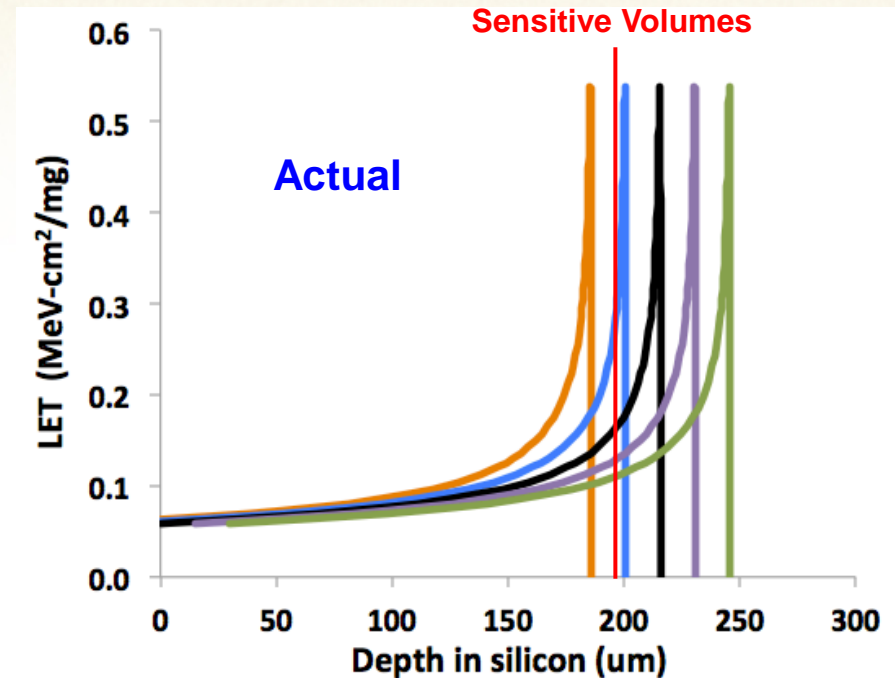
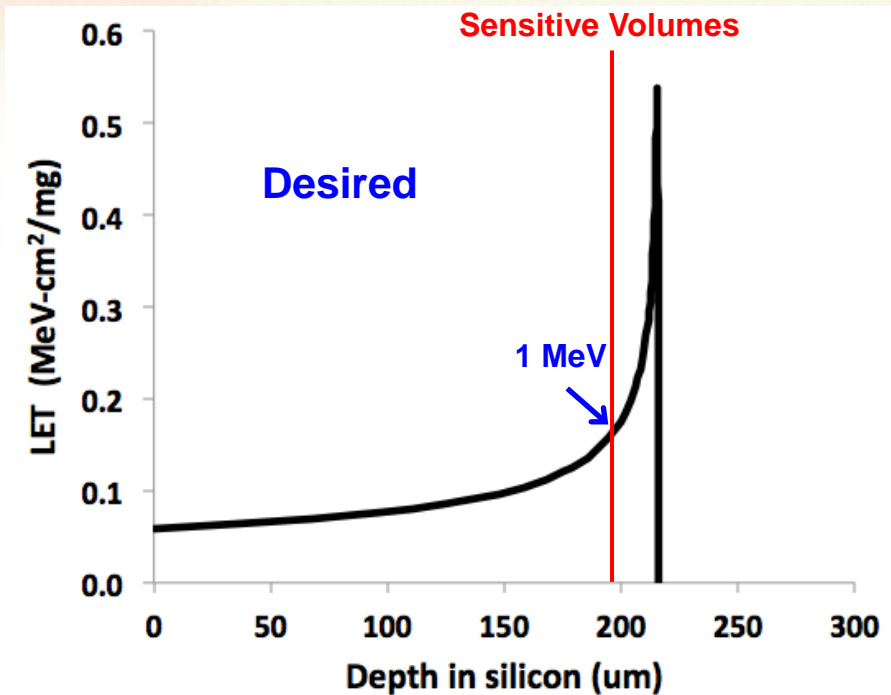
65 nm SRAM



[Sierawski *et al.*, TNS 2009]

- Historically, protons only caused SEEs through nuclear reactions
- PDI also causes SEEs in modern ICs

Proton Energy Stragggle



Ways to minimize energy stragggle:

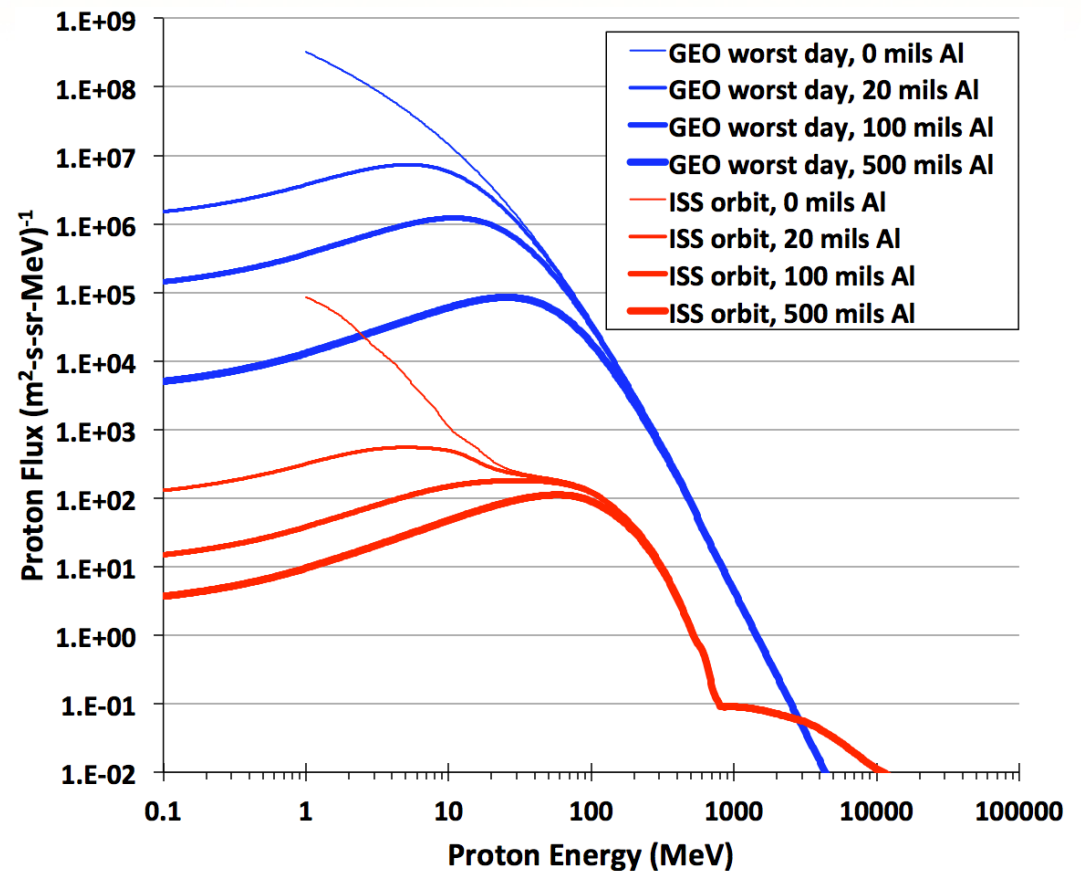
- Test with low initial beam energies, in vacuum, without degraders
- Decapsulate DUT. Thin the substrate if DUT is flip chip
- Test at 0° angle

Proton energy stragggle forced previous studies to either

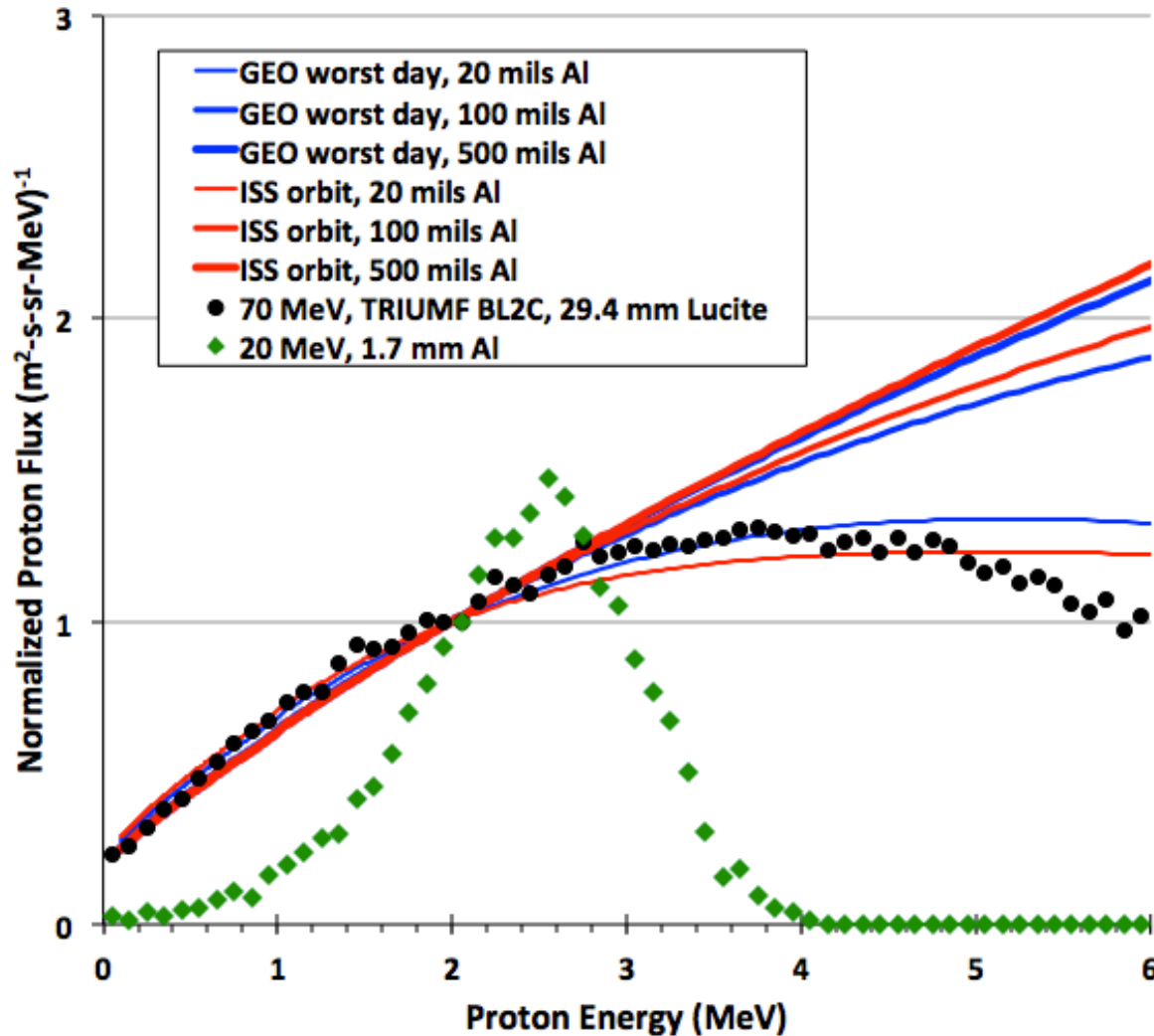
1. Only use data qualitatively
2. Build a calibrated model [Sierawski TNS 2009]

Space Proton Environments

- All shielded space environments have qualitatively similar low-energy proton spectra, regardless of
 - Orbit
 - Solar conditions
 - Shielding thickness
 - Shielding material
- Assumption: Only protons that reach SVs with < 3 MeV can cause errors through PDI

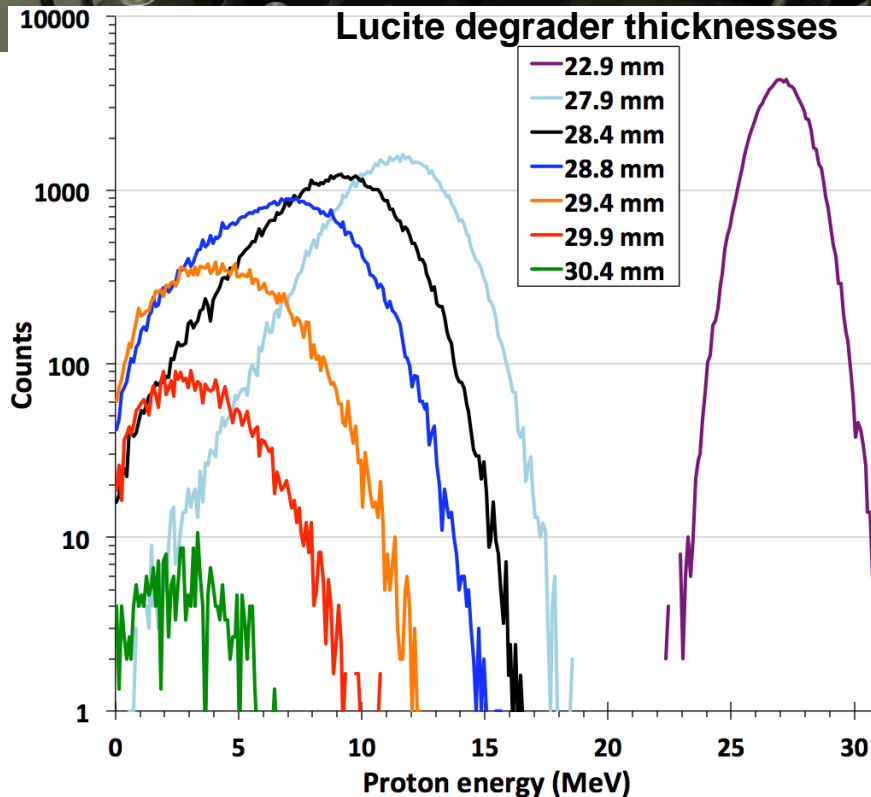
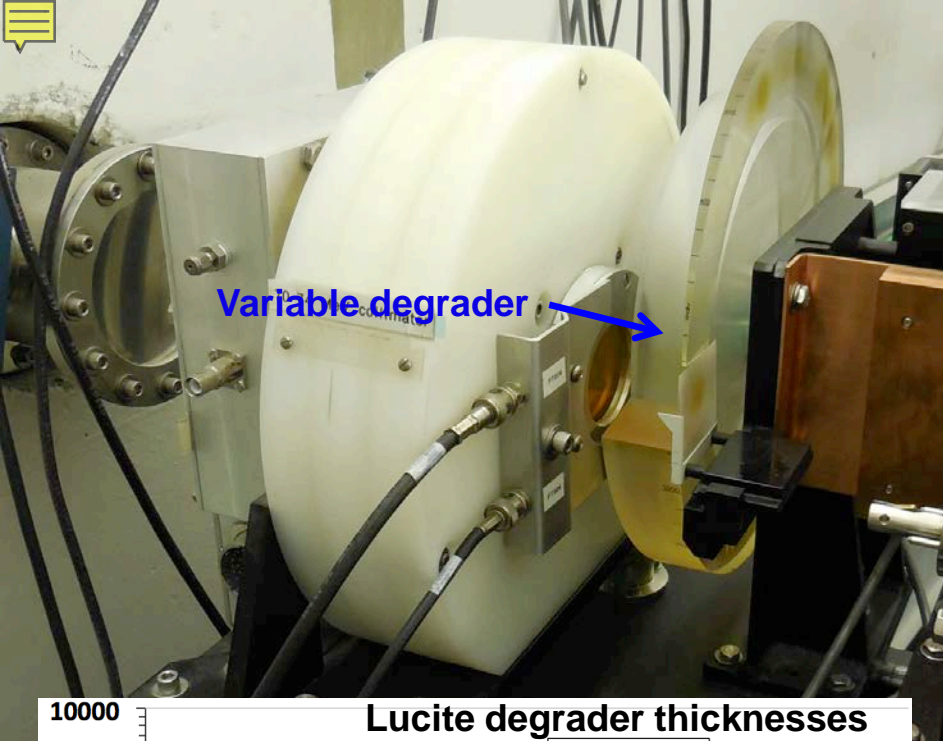


A space-like energy spectrum, in the lab!



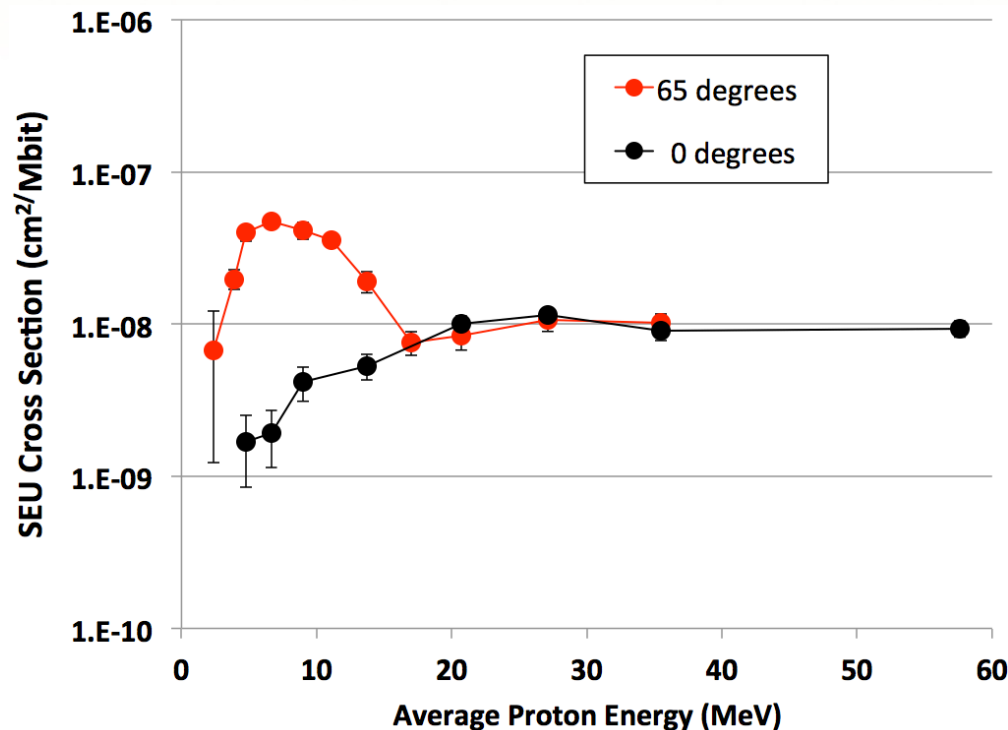
- 70 MeV proton beam can be degraded to reproduce space's sub 3 MeV energy spectrum
- Degraded 20 MeV beam has insufficient energy straggle to reproduce space's sub 3 MeV energy spectrum
 - **Energy straggle helps us reproduce environment of interest**

TRIUMF's proton beamline



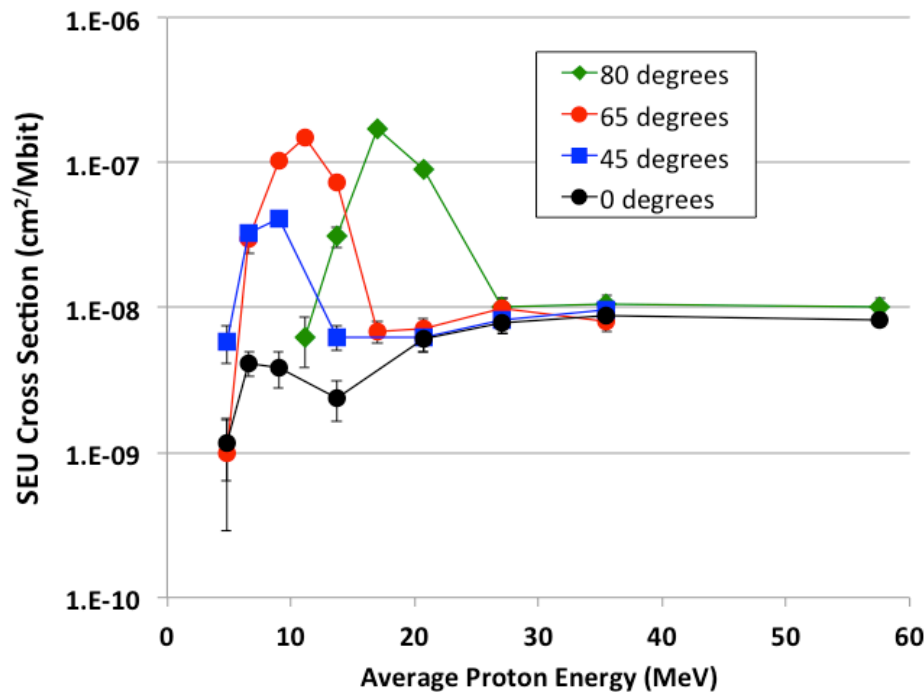
- Increasing degrader thickness decreases the average proton energy
- Certain range of degrader thicknesses maximizes flux of sub 3 MeV protons
- 1-Mbit IBM 65 nm SOI SRAMs were irradiated at 0.8 V, room temperature

SRAM with no substrate

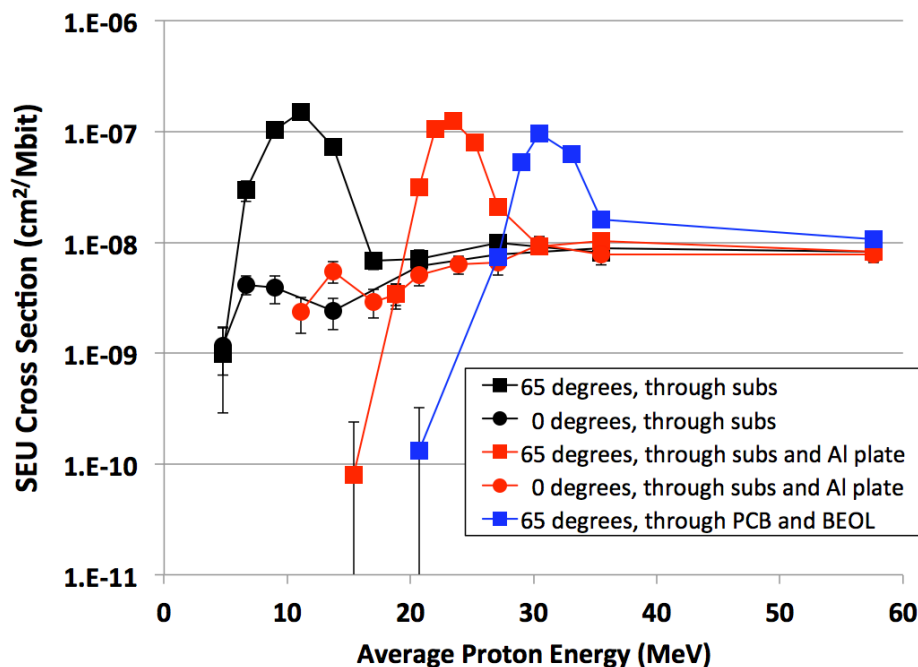


- Substrate removed down to BOX using XeF₂ etch [Shaneyfelt *et al.*, TNS 2012]
- Backside irradiation through only 150 nm BOX → same energy spectrum reached SVs at 0° and 65° angles
- 65° cross sections higher due to higher effective LET
 - **PDI rate predictions must account for angular response. Angled tests not usually done due to increased energy straggle**

Angular response

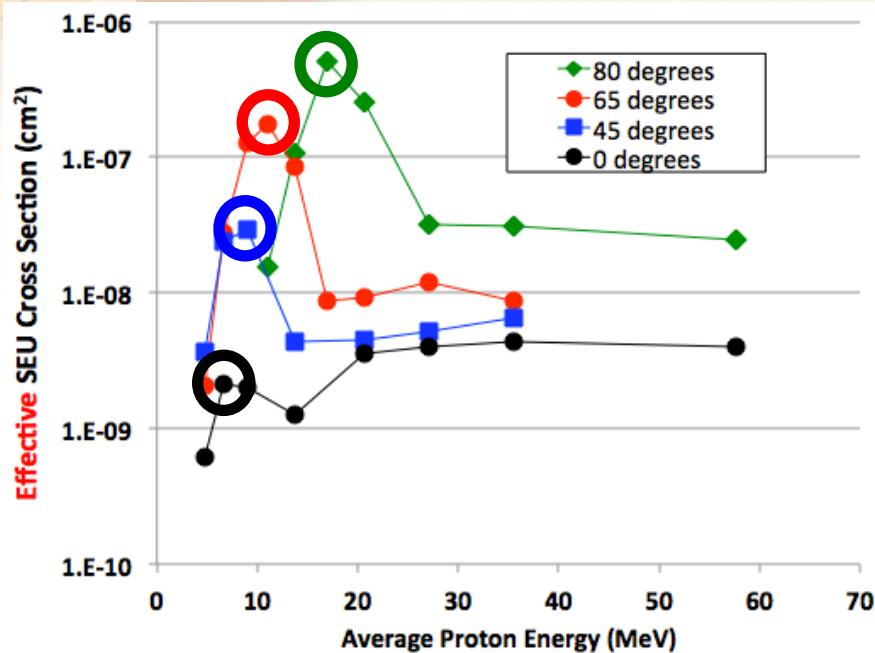


- Irradiated from backside through BOX and 350 um substrate
- Increasing angle
 - ➔ increases effective LET
 - ➔ increases peak cross section
 - ➔ **improves PDI susceptibility detection** beyond that of 0° method from [Schwank *et al.*, TNS 2012]

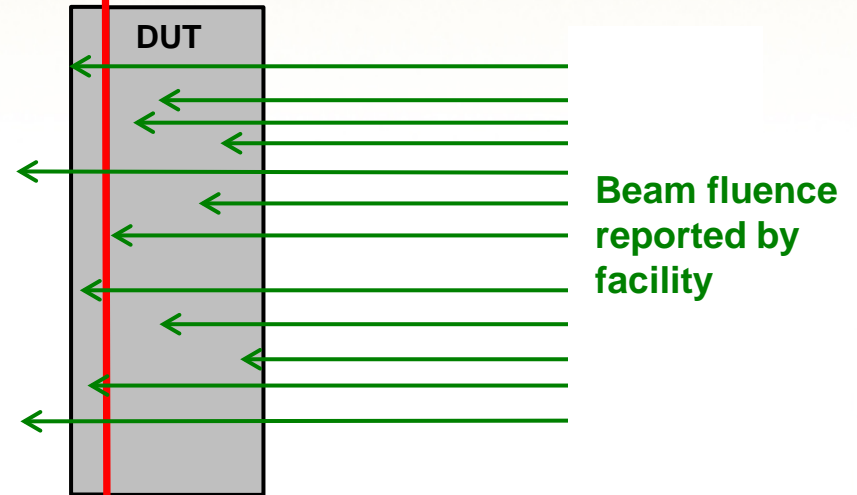


- Tests also work well on encapsulated parts

PDI Error Rate Calculation



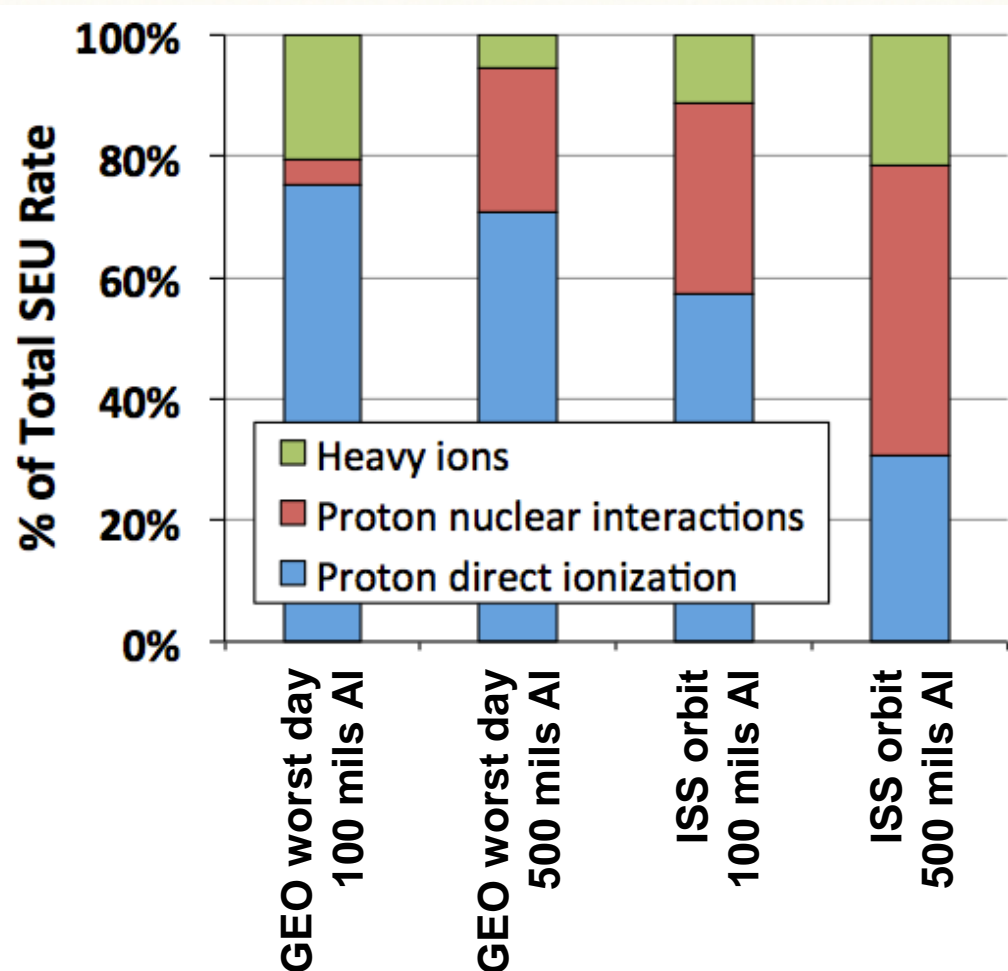
Sensitive Volumes



Angle	Effective Peak SEU Cross Section (cm ² /Mbit)	Fraction of fluence that reaches sensitive volume plane with < 3 MeV	SEU Cross Section for < 3 MeV space protons (cm ² /Mbit)	Probability proton strikes at this angle	SEU Cross Section for isotropic < 3 MeV space protons (cm ² /Mbit)
0°	4.2E-09	0.143	2.9E-08	0.18 (0°-35°)	3.0E-06
45°	5.8E-08	0.128	4.5E-07	0.25 (35°-55°)	
65°	3.5E-07	0.127	2.8E-06	0.31 (55°-75°)	
80°	9.8E-07	0.125	7.8E-06	0.26 (75°-90°)	

Predicted contributions to SEU rate

- Heavy ion rate prediction used data from [Heidel *et al.*, TNS 2009]



Summary

- **A high-energy proton beam can be degraded to produce a low-energy spectrum that matches that of all shielded space environments**
 - **This observation could dramatically simplify PDI rate prediction, allowing tests at high-energy facilities, on encapsulated parts, without knowledge of circuit design**
- **Increasing beam angle increases proton effective LET and measured cross sections**
- **Susceptibility to PDI effects is best identified at large angles of incidence when using a degraded high-energy proton beam**